Applicant(s)/Patent Under Application/Control No. Reexamination 10/659,219 JEUTTER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 -Edna Wong 1753 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification, Country Code-Number-Kind Code MM-YYYY US-5,800,695 09-1998 Kang et al. Α 205/135 * US-6,335,078 01-2002 В Venkataramani et al. 428/139 US-С US-D US-Ε F US-G US-USн USı US-J US-K US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 01100302 A Ν 04-1989 Japan YAMAMOTO et al. F01D 5/28 EP 1076107 A1 02-2001 O **European Patent** BEECK et al. C23C 4/00 Р Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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